

# Woojin Jeon

## List of Publications by Year in Descending Order

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

61  
papers

1,320  
citations

19  
h-index

35  
g-index

63  
ext. papers

1,534  
ext. citations

6.2  
avg, IF

4.52  
L-index

#	Paper	IF	Citations
61	Controlling the crystallinity of HfO <sub>2</sub> thin film using the surface energy-driven phase stabilization and template effect. <i>Applied Surface Science</i> , <b>2022</b> , 590, 153082	6.7	0
60	Chemistry of ruthenium as an electrode for metal-insulator-metal capacitor application. <i>Nanotechnology</i> , <b>2021</b> , 32, 045201	3.4	0
59	The Significance on Structural Modulation of Buffer and Gate Insulator for ALD Based InGaZnO TFT Applications. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 1-7	2.9	1
58	Y-doped HfO <sub>2</sub> deposited by atomic layer deposition using a cocktail precursor for DRAM capacitor dielectric application. <i>Ceramics International</i> , <b>2021</b> , 48, 3236-3236	5.1	3
57	Improved Properties of the Atomic Layer Deposited Ru Electrode for Dynamic Random-Access Memory Capacitor Using Discrete Feeding Method. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2021</b> , 13, 23915-23927	9.5	0
56	Highly sustainable mechanical/electrical resistance switching behaviors via one-dimensional Ag/TiO <sub>2</sub> core-shell resistive switchable materials in flexible composite. <i>Organic Electronics</i> , <b>2021</b> , 88, 105968	3.5	1
55	Modulation of the adsorption chemistry of a precursor in atomic layer deposition to enhance the growth per cycle of a TiO thin film. <i>Physical Chemistry Chemical Physics</i> , <b>2021</b> , 23, 2568-2574	3.6	0
54	An Empirical Investigation on the Effect of Oxygen Vacancy in ZrO <sub>2</sub> Thin Film on the Frequency-Dependent Capacitance Degradation in the Metal-Insulator-Metal Capacitor. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 1-5	2.9	1
53	A visible-light phototransistor based on the heterostructure of ZnO and TiO with trap-assisted photocurrent generation.. <i>RSC Advances</i> , <b>2021</b> , 11, 12051-12057	3.7	4
52	Improving the photodetection and stability of a visible-light QDs/ZnO phototransistor via an Al <sub>2</sub> O <sub>3</sub> additional layer. <i>Journal of Materials Chemistry C</i> , <b>2021</b> , 9, 2550-2560	7.1	4
51	Optimized Al-doped TiO <sub>2</sub> gate insulator for a metal-oxide-semiconductor capacitor on a Ge substrate. <i>Journal of Materials Chemistry C</i> , <b>2021</b> , 9, 1572-1583	7.1	1
50	Investigating the interface characteristics of high-k ZrO <sub>2</sub> /SiO <sub>2</sub> stacked gate insulator grown by plasma-enhanced atomic layer deposition for improving the performance of InSnZnO thin film transistors. <i>AIP Advances</i> , <b>2020</b> , 10, 015239	1.5	1
49	Modulated filamentary conduction of Ag/TiO <sub>2</sub> core-shell nanowires to impart extremely sustained resistance switching behavior in a flexible composite. <i>Applied Materials Today</i> , <b>2020</b> , 19, 100569	6.6	7
48	Atomic layer deposition of Ru thin films using (2,4-dimethyloxopentadienyl)(ethylcyclopentadienyl)Ru and the effect of ammonia treatment during the deposition. <i>Journal of Materials Chemistry C</i> , <b>2020</b> , 8, 6993-7004	7.1	8
47	Recent advances in the understanding of high-k dielectric materials deposited by atomic layer deposition for dynamic random-access memory capacitor applications. <i>Journal of Materials Research</i> , <b>2020</b> , 35, 775-794	2.5	23
46	Improving the photoresponsivity and reducing the persistent photocurrent effect of visible-light ZnO/quantum-dot phototransistors via a TiO <sub>2</sub> layer. <i>Journal of Materials Chemistry C</i> , <b>2020</b> , 8, 16384-16391	7.1	5
45	Sustainable resistance switching performance from composite-type ReRAM device based on carbon Nanotube@Titania core-shell wires. <i>Scientific Reports</i> , <b>2020</b> , 10, 18830	4.9	2

44	Comparative Study on the Gate-Induced Electrical Instability of p-Type SnO Thin-Film Transistors with SiO <sub>2</sub> and Al <sub>2</sub> O <sub>3</sub> /SiO <sub>2</sub> Gate Dielectrics. <i>Physica Status Solidi - Rapid Research Letters</i> , <b>2020</b> , 14, 2000304	3.5	1
43	Nanoscale surface engineering of a high-k ZrO <sub>2</sub> /SiO <sub>2</sub> gate insulator for a high performance ITZO TFT via plasma-enhanced atomic layer deposition. <i>Journal of Materials Chemistry C</i> , <b>2020</b> , 8, 13342-13348	7.1	1
42	Substrate Effects on the Growth Behavior of Atomic-Layer-Deposited Ru Thin Films Using RuO <sub>4</sub> Precursor and N <sub>2</sub> /H <sub>2</sub> Mixed Gas. <i>Journal of Physical Chemistry C</i> , <b>2019</b> , 123, 22539-22549	3.8	5
41	The impact of plasma-enhanced atomic layer deposited ZrSiO <sub>x</sub> insulators on low voltage operated In-Sn-Zn-O thin film transistors. <i>Ceramics International</i> , <b>2019</b> , 45, 19166-19172	5.1	8
40	Scaling the Equivalent Oxide Thickness by Employing a TiO <sub>2</sub> Thin Film on a ZrO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> -Based Dielectric for Further Scaling of Dynamic Random Access Memory. <i>Physica Status Solidi - Rapid Research Letters</i> , <b>2019</b> , 13, 1900282	2.5	5
39	Improved performance and stability of In-Sn-Zn-O thin film transistor by introducing a meso-crystalline ZrO <sub>2</sub> high-k gate insulator. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2019</b> , 37, 020924	2.9	10
38	Controlling the Current Conduction Asymmetry of HfO <sub>2</sub> Metal/Insulator/Metal Diodes by Interposing Al <sub>2</sub> O <sub>3</sub> Layer. <i>IEEE Transactions on Electron Devices</i> , <b>2019</b> , 66, 402-406	2.9	6
37	Optimization of a SiO <sub>x</sub> /SiN <sub>x</sub> O <sub>y</sub> C <sub>z</sub> multilayer structure for a reliable gas diffusion barrier via low-temperature plasma-enhanced atomic layer deposition. <i>Ceramics International</i> , <b>2019</b> , 45, 7407-7412	5.1	3
36	Controlling the Electrical Characteristics of ZrO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /ZrO <sub>2</sub> Capacitors by Adopting a Ru Top Electrode Grown via Atomic Layer Deposition. <i>Physica Status Solidi - Rapid Research Letters</i> , <b>2019</b> , 13, 1800454	2.5	13
35	Quantitative Analysis of the Incorporation Behaviors of Sr and Ti Atoms During the Atomic Layer Deposition of SrTiO Thin Films. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2018</b> , 10, 8836-8844	9.5	15
34	Resistance Switching Capable Polymer Nanocomposites Employing Networks of One-Dimensional Nanocarbon Wrapped by TiO <sub>2</sub> Conformal Layer. <i>IEEE Nanotechnology Magazine</i> , <b>2018</b> , 17, 567-573	2.6	0
33	Demonstrating the Ultrathin Metal/Insulator/Metal Diode Using TiN/ZrO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /ZrO <sub>2</sub> Stack by Employing RuO <sub>2</sub> Top Electrode. <i>IEEE Transactions on Electron Devices</i> , <b>2018</b> , 65, 660-666	2.9	12
32	Chemistry of SiN <sub>x</sub> thin film deposited by plasma-enhanced atomic layer deposition using di-isopropylaminosilane (DIPAS) and N <sub>2</sub> plasma. <i>Ceramics International</i> , <b>2018</b> , 44, 20890-20895	5.1	6
31	Electrical Properties of ZrO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /ZrO <sub>2</sub> -Based Capacitors with TiN, Ru, and TiN/Ru Top Electrode Materials. <i>Physica Status Solidi - Rapid Research Letters</i> , <b>2018</b> , 12, 1800356	2.5	12
30	Wafer-Scale Synthesis of Reliable High-Mobility Molybdenum Disulfide Thin Films via Inhibitor-Utilizing Atomic Layer Deposition. <i>Advanced Materials</i> , <b>2017</b> , 29, 1703031	24	33
29	Depletion effect of polycrystalline-silicon gate electrode by phosphorus deactivation. <i>Solid-State Electronics</i> , <b>2017</b> , 127, 1-4	1.7	0
28	Physisorbed-precursor-assisted atomic layer deposition of reliable ultrathin dielectric films on inert graphene surfaces for low-power electronics. <i>2D Materials</i> , <b>2016</b> , 3, 035027	5.9	12
27	Frustration of Negative Capacitance in Al <sub>2</sub> O <sub>3</sub> /BaTiO <sub>3</sub> Bilayer Structure. <i>Scientific Reports</i> , <b>2016</b> , 6, 19039	4.9	37

26	Vapor Transport Synthesis of Two-Dimensional SnS <sub>2</sub> Nanocrystals Using a SnS <sub>2</sub> Precursor Obtained from the Sulfurization of SnO <sub>2</sub> . <i>Crystal Growth and Design</i> , <b>2016</b> , 16, 3884-3889	3.5	19
25	Mesostructured Hf <sub>x</sub> Al <sub>y</sub> O <sub>2</sub> Thin Films as Reliable and Robust Gate Dielectrics with Tunable Dielectric Constants for High-Performance Graphene-Based Transistors. <i>ACS Nano</i> , <b>2016</b> , 10, 6659-66	16.7	15
24	Improved Initial Growth Behavior of SrO and SrTiO <sub>3</sub> Films Grown by Atomic Layer Deposition Using {Sr(demamp)(tmhd)} <sub>2</sub> as Sr-Precursor. <i>Chemistry of Materials</i> , <b>2015</b> , 27, 3881-3891	9.6	29
23	High-concentration boron doping of graphene nanoplatelets by simple thermal annealing and their supercapacitive properties. <i>Scientific Reports</i> , <b>2015</b> , 5, 9817	4.9	86
22	Reducing the nano-scale defect formation of atomic-layer-deposited SrTiO <sub>3</sub> films by adjusting the cooling rate of the crystallization annealing of the seed layer. <i>Thin Solid Films</i> , <b>2015</b> , 589, 723-729	2.2	8
21	Interfacial charge-induced polarization switching in Al <sub>2</sub> O <sub>3</sub> /Pb(Zr,Ti)O <sub>3</sub> bi-layer. <i>Journal of Applied Physics</i> , <b>2015</b> , 118, 224105	2.5	24
20	Asymmetry in electrical properties of Al-doped TiO <sub>2</sub> film with respect to bias voltage. <i>Physica Status Solidi - Rapid Research Letters</i> , <b>2015</b> , 9, 410-413	2.5	9
19	High-throughput fabrication of infinitely long 10 nm slit arrays for terahertz applications. <i>Journal of Infrared, Millimeter, and Terahertz Waves</i> , <b>2015</b> , 36, 262-268	2.2	24
18	Controlling the Al-doping profile and accompanying electrical properties of rutile-phased TiO <sub>2</sub> thin films. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2014</b> , 6, 7910-7	9.5	18
17	Structure and electrical properties of Al-doped HfO <sub>2</sub> and ZrO <sub>2</sub> films grown via atomic layer deposition on Mo electrodes. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2014</b> , 6, 22474-82	9.5	48
16	Grain size engineering for ferroelectric Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> films by an insertion of Al <sub>2</sub> O <sub>3</sub> interlayer. <i>Applied Physics Letters</i> , <b>2014</b> , 105, 192903	3.4	134
15	Chemistry of active oxygen in RuO <sub>x</sub> and its influence on the atomic layer deposition of TiO <sub>2</sub> films. <i>Journal of Materials Chemistry C</i> , <b>2014</b> , 2, 9993-10001	7.1	15
14	Ferroelectric properties and switching endurance of Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> films on TiN bottom and TiN or RuO <sub>2</sub> top electrodes. <i>Physica Status Solidi - Rapid Research Letters</i> , <b>2014</b> , 8, 532-535	2.5	102
13	Evaluating the top electrode material for achieving an equivalent oxide thickness smaller than 0.4 nm from an Al-doped TiO <sub>2</sub> film. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2014</b> , 6, 21632-7	9.5	23
12	Highly improved uniformity in the resistive switching parameters of TiO <sub>2</sub> thin films by inserting Ru nanodots. <i>Advanced Materials</i> , <b>2013</b> , 25, 1987-92	24	152
11	Titanium dioxide thin films for next-generation memory devices. <i>Journal of Materials Research</i> , <b>2013</b> , 28, 313-325	2.5	56
10	Atomic Layer Deposition of SrTiO <sub>3</sub> Films with Cyclopentadienyl-Based Precursors for Metal/Insulator/Metal Capacitors. <i>Chemistry of Materials</i> , <b>2013</b> , 25, 953-961	9.6	61
9	32 B <sub>2</sub> Crossbar Array Resistive Memory Composed of a Stacked Schottky Diode and Unipolar Resistive Memory. <i>Advanced Functional Materials</i> , <b>2013</b> , 23, 1440-1449	15.6	136

8	Resistive Memory: 32 B2 Crossbar Array Resistive Memory Composed of a Stacked Schottky Diode and Unipolar Resistive Memory (Adv. Funct. Mater. 11/2013). <i>Advanced Functional Materials</i> , <b>2013</b> , 23, 1350-1350	15.6	2
7	Controlling the initial growth behavior of SrTiO <sub>3</sub> films by interposing Al <sub>2</sub> O <sub>3</sub> layers between the film and the Ru substrate. <i>Journal of Materials Chemistry</i> , <b>2012</b> , 22, 15037		19
6	Growth of Conductive SrRuO <sub>3</sub> Films by Combining Atomic Layer Deposited SrO and Chemical Vapor Deposited RuO <sub>2</sub> Layers. <i>Chemistry of Materials</i> , <b>2012</b> , 24, 4686-4692	9.6	24
5	Impact of bimetal electrodes on dielectric properties of TiO <sub>2</sub> and Al-doped TiO <sub>2</sub> films. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2012</b> , 4, 4726-30	9.5	16
4	Optimization of chemical structure of Schottky-type selection diode for crossbar resistive memory. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2012</b> , 4, 5338-45	9.5	9
3	One-dimensional TiO <sub>2</sub> @Ag nanoarchitectures with interface-mediated implementation of resistance-switching behavior in polymer nanocomposites. <i>ACS Applied Materials &amp; Interfaces</i> , <b>2012</b> , 4, 5727-31	9.5	18
2	TiO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /TiO <sub>2</sub> Nanolaminated Thin Films for DRAM Capacitor Deposited by Plasma-Enhanced Atomic Layer Deposition. <i>Electrochemical and Solid-State Letters</i> , <b>2008</b> , 11, H19		30
1	Nanosession: Atomic Layer Deposition419-428		